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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

E-XF

Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I <sup>2</sup> C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	68-VFQFN Exposed Pad
Supplier Device Package	68-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3246lti-149t

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#### Figure 2-6. 100-pin TQFP Part Pinout



#### Table 2-1. VDDIO and Port Pin Associations

VDDIO	Port Pins
VDDIO0	P0[7:0], P4[7:0], P12[3:2]
VDDIO1	P1[7:0], P5[7:0], P12[7:6]
VDDIO2	P2[7:0], P6[7:0], P12[5:4], P15[5:4]
VDDIO3	P3[7:0], P12[1:0], P15[3:0]
VDDD	P15[7:6] (USB D+, D-)

Note 9. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.



# Table 4-4. Boolean Instructions

Mnemonic	Description	Bytes	Cycles
CLR C	Clear carry	1	1
CLR bit	Clear direct bit	2	3
SETB C	Set carry	1	1
SETB bit	Set direct bit	2	3
CPL C	Complement carry	1	1
CPL bit	Complement direct bit	2	3
ANL C, bit	AND direct bit to carry	2	2
ANL C, /bit	AND complement of direct bit to carry	2	2
ORL C, bit	OR direct bit to carry	2	2
ORL C, /bit	OR complement of direct bit to carry	2	2
MOV C, bit	Move direct bit to carry	2	2
MOV bit, C	Move carry to direct bit	2	3
JC rel	Jump if carry is set	2	3
JNC rel	Jump if no carry is set	2	3
JB bit, rel	Jump if direct bit is set	3	5
JNB bit, rel	Jump if direct bit is not set	3	5
JBC bit, rel	Jump if direct bit is set and clear bit	3	5



## Table 4-8. Interrupt Vector Table

#	Fixed Function	DMA	UDB
0	LVD	phub_termout0[0]	udb_intr[0]
1	Cache/ECC	phub_termout0[1]	udb_intr[1]
2	Reserved	phub_termout0[2]	udb_intr[2]
3	Sleep (Pwr Mgr)	phub_termout0[3]	udb_intr[3]
4	PICU[0]	phub_termout0[4]	udb_intr[4]
5	PICU[1]	phub_termout0[5]	udb_intr[5]
6	PICU[2]	phub_termout0[6]	udb_intr[6]
7	PICU[3]	phub_termout0[7]	udb_intr[7]
8	PICU[4]	phub_termout0[8]	udb_intr[8]
9	PICU[5]	phub_termout0[9]	udb_intr[9]
10	PICU[6]	phub_termout0[10]	udb_intr[10]
11	PICU[12]	phub_termout0[11]	udb_intr[11]
12	PICU[15]	phub_termout0[12]	udb_intr[12]
13	Comparators Combined	phub_termout0[13]	udb_intr[13]
14	Reserved	phub_termout0[14]	udb_intr[14]
15	l <sup>2</sup> C	phub_termout0[15]	udb_intr[15]
16	Reserved	phub_termout1[0]	udb_intr[16]
17	Timer/Counter0	phub_termout1[1]	udb_intr[17]
18	Timer/Counter1	phub_termout1[2]	udb_intr[18]
19	Timer/Counter2	phub_termout1[3]	udb_intr[19]
20	Timer/Counter3	phub_termout1[4]	udb_intr[20]
21	USB SOF Int	phub_termout1[5]	udb_intr[21]
22	USB Arb Int	phub_termout1[6]	udb_intr[22]
23	USB Bus Int	phub_termout1[7]	udb_intr[23]
24	USB Endpoint[0]	phub_termout1[8]	udb_intr[24]
25	USB Endpoint Data	phub_termout1[9]	udb_intr[25]
26	Reserved	phub_termout1[10]	udb_intr[26]
27	LCD	phub_termout1[11]	udb_intr[27]
28	Reserved	phub_termout1[12]	udb_intr[28]
29	Decimator Int	phub_termout1[13]	udb_intr[29]
30	PHUB Error Int	phub_termout1[14]	udb_intr[30]
31	EEPROM Fault Int	phub_termout1[15]	udb_intr[31]



boost typically draws 250  $\mu$ A in active mode and 25  $\mu$ A in standby mode. The boost operating modes must be used in conjunction with chip power modes to minimize total power consumption. Table 6-4 lists the boost power modes available in different chip power modes.

Table 6-4. Chip and Boost Power Modes Compatibility

Chip Power Modes	Boost Power Modes
Chip-active or alternate active mode	Boost must be operated in its active mode.
Chip-sleep mode	Boost can be operated in either active or standby mode. In boost standby mode, the chip must wake up periodi- cally for boost active-mode refresh.
Chip-hibernate mode	Boost can be operated in its active mode. However, it is recommended not to use the boost in chip hibernate mode due to the higher current consumption in boost active mode.

#### 6.2.2.1 Boost Firmware Requirements

To ensure boost inrush current is within specification at startup, the **Enable Fast IMO During Startup** value must be unchecked in the PSoC Creator IDE. The **Enable Fast IMO During Startup** option is found in PSoC Creator in the design wide resources (cydwr) file **System** tab. Un-checking this option configures the device to run at 12 MHz vs 48 MHz during startup while configuring the device. The slower clock speed results in reduced current draw through the boost circuit.

# 6.2.2.2 Boost Design Process

Correct operation of the boost converter requires specific component values determined for each designs unique operating conditions. The  $C_{BAT}$  capacitor, Inductor, Schottky diode, and  $C_{BOOST}$  capacitor components are required with the values specified in the electrical specifications, Table 11-7 on page 74. The only variable component value is the inductor  $L_{BOOST}$  which is primarily sized for correct operation of the boost across operating conditions and secondarily for efficiency. Additional operating region constraints exist for  $V_{OUT}$ ,  $V_{BAT}$ ,  $I_{OUT}$ , and  $T_A$ .

The following steps must be followed to determine boost converter operating parameters and  $L_{BOOST}$  value.

- 1. Choose desired V<sub>BAT</sub>, V<sub>OUT</sub>, T<sub>A</sub>, and I<sub>OUT</sub> operating condition ranges for the application.
- 2. Determine if  $V_{BAT}$  and  $V_{OUT}$  ranges fit the boost operating range based on the  $T_A$  range over  $V_{BAT}$  and  $V_{OUT}$  chart, Figure 11-8 on page 74. If the operating ranges are not met, modify the operating conditions or use an external boost regulator.
- 3. Determine if the desired ambient temperature ( $T_A$ ) range fits the ambient temperature operating range based on the  $T_A$ **range over V<sub>BAT</sub> and V<sub>OUT</sub>** chart, Figure 11-8 on page 74. If the temperature range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.
- Determine if the desired output current (I<sub>OUT</sub>) range fits the output current operating range based on the I<sub>OUT</sub> range over V<sub>BAT</sub> and V<sub>OUT</sub> chart, Figure 11-9 on page 74. If the output

current range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.

- Find the allowed inductor values based on the L<sub>BOOST</sub> values over V<sub>BAT</sub> and V<sub>OUT</sub> chart, Figure 11-10 on page 74.
- 6. Based on the allowed inductor values, inductor dimensions, inductor cost, boost efficiency, and  $V_{RIPPLE}$  choose the optimum inductor value for the system. Boost efficiency and  $V_{RIPPLE}$  typical values are provided in the **Efficiency vs V\_BAT** and **V\_{RIPPLE} vs V\_BAT** charts, Figure 11-11 on page 75 through Figure 11-14 on page 75. In general, if high efficiency and low  $V_{RIPPLE}$  are most important, then the highest allowed inductor value should be used. If low inductor cost or small inductor size are most important, then one of the smaller allowed inductor (s) efficiency,  $V_{RIPPLE}$ , cost or dimensions are not acceptable for the application than an external boost regulator should be used.

# 6.3 Reset

CY8C32 has multiple internal and external reset sources available. The reset sources are:

- Power source monitoring The analog and digital power voltages, VDDA, VDDD, VCCA, and VCCD are monitored in several different modes during power up, active mode, and sleep mode (buzzing). If any of the voltages goes outside predetermined ranges then a reset is generated. The monitors are programmable to generate an interrupt to the processor under certain conditions before reaching the reset thresholds.
- External The device can be reset from an external source by pulling the reset pin (XRES) low. The XRES pin includes an internal pull-up to VDDIO1. VDDD, VDDA, and VDDIO1 must all have voltage applied before the part comes out of reset.
- Watchdog timer A watchdog timer monitors the execution of instructions by the processor. If the watchdog timer is not reset by firmware within a certain period of time, the watchdog timer generates a reset.
- Software The device can be reset under program control.

#### Figure 6-8. Resets







#### Figure 6-10. SIO Input/Output Block Diagram

Figure 6-11. USBIO Block Diagram





The USBIO pins (P15[7] and P15[6]), when enabled for I/O mode, have limited drive mode control. The drive mode is set using the PRT15.DM0[7, 6] register. A resistive pull option is also available at the USBIO pins, which can be enabled using the PRT15.DM1[7, 6] register. When enabled for USB mode, the drive mode control has no impact on the configuration of the USB pins. Unlike the GPIO and SIO configurations, the port wide configuration registers do not configure the USB drive mode bits. Table 6-7 shows the drive mode configuration for the USBIO pins.

PRT15.DM1[7,6] Pull up enable	PRT15.DM0[7,6] Drive Mode enable	PRT15.DR[7,6] = 1	PRT15.DR[7,6] = 0	Description
0	0	High Z	Strong Low	Open Drain, Strong Low
0	1	Strong High	Strong Low	Strong Outputs
1	0	Res High (5k)	Strong Low	Resistive Pull Up, Strong Low
1	1	Strong High	Strong Low	Strong Outputs

# Table 6-7. USBIO Drive Modes (P15[7] and P15[6])

#### High Impedance Analog

The default reset state with both the output driver and digital input buffer turned off. This prevents any current from flowing in the I/O's digital input buffer due to a floating voltage. This state is recommended for pins that are floating or that support an analog voltage. High impedance analog pins do not provide digital input functionality.

To achieve the lowest chip current in sleep modes, all I/Os must either be configured to the high impedance analog mode, or have their pins driven to a power supply rail by the PSoC device or by external circuitry.

High Impedance Digital

The input buffer is enabled for digital signal input. This is the standard high impedance (HiZ) state recommended for digital inputs.

Resistive pull-up or resistive pull-down

Resistive pull-up or pull-down, respectively, provides a series resistance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. Interfacing to mechanical switches is a common application for these modes. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

Open Drain, Drives High and Open Drain, Drives Low

Open drain modes provide high impedance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. A common application for these modes is driving the  $I^2C$  bus signal lines.

Strong Drive

Provides a strong CMOS output drive in either high or low state. This is the standard output mode for pins. Strong Drive mode pins must not be used as inputs under normal circumstances. This mode is often used to drive digital output signals or external FETs.

Resistive pull-up and pull-down

Similar to the resistive pull-up and resistive pull-down modes except the pin is always in series with a resistor. The high data state is pull-up while the low data state is pull-down. This mode is most often used when other signals that may cause shorts can drive the bus. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

### 6.4.2 Pin Registers

Registers to configure and interact with pins come in two forms that may be used interchangeably.

All I/O registers are available in the standard port form, where each bit of the register corresponds to one of the port pins. This register form is efficient for quickly reconfiguring multiple port pins at the same time.

I/O registers are also available in pin form, which combines the eight most commonly used port register bits into a single register for each pin. This enables very fast configuration changes to individual pins with a single register write.

#### 6.4.3 Bidirectional Mode

High-speed bidirectional capability allows pins to provide both the high impedance digital drive mode for input signals and a second user selected drive mode such as strong drive (set using PRT×DM[2:0] registers) for output signals on the same pin, based on the state of an auxiliary control bus signal. The bidirectional capability is useful for processor busses and communications interfaces such as the SPI Slave MISO pin that requires dynamic hardware control of the output buffer.

The auxiliary control bus routes up to 16 UDB or digital peripheral generated output enable signals to one or more pins.

# 6.4.4 Slew Rate Limited Mode

GPIO and SIO pins have fast and slow output slew rate options for strong and open drain drive modes, not resistive drive modes. Because it results in reduced EMI, the slow edge rate option is recommended for signals that are not speed critical, generally less than 1 MHz. The fast slew rate is for signals between 1 MHz and 33 MHz. The slew rate is individually configurable for each pin, and is set by the PRT×SLW registers.



# 7.2 Universal Digital Block

The Universal Digital Block (UDB) represents an evolutionary step to the next generation of PSoC embedded digital peripheral functionality. The architecture in first generation PSoC digital blocks provides coarse programmability in which a few fixed functions with a small number of options are available. The new UDB architecture is the optimal balance between configuration granularity and efficient implementation. A cornerstone of this approach is to provide the ability to customize the devices digital operation to match application requirements.

To achieve this, UDBs consist of a combination of uncommitted logic (PLD), structured logic (Datapath), and a flexible routing scheme to provide interconnect between these elements, I/O connections, and other peripherals. UDB functionality ranges from simple self contained functions that are implemented in one UDB, or even a portion of a UDB (unused resources are available for other functions), to more complex functions that require multiple UDBs. Examples of basic functions are timers, counters, CRC generators, PWMs, dead band generators, and communications functions, such as UARTs, SPI, and I<sup>2</sup>C. Also, the PLD blocks and connectivity provide full featured general purpose programmable logic within the limits of the available resources.

### Figure 7-2. UDB Block Diagram



Routing Channel

The main component blocks of the UDB are:

- PLD blocks There are two small PLDs per UDB. These blocks take inputs from the routing array and form registered or combinational sum-of-products logic. PLDs are used to implement state machines, state bits, and combinational logic equations. PLD configuration is automatically generated from graphical primitives.
- Datapath Module This 8-bit wide datapath contains structured logic to implement a dynamically configurable ALU, a variety of compare configurations and condition generation. This block also contains input/output FIFOs, which are the primary parallel data interface between the CPU/DMA system and the UDB.

- Status and Control Module The primary role of this block is to provide a way for CPU firmware to interact and synchronize with UDB operation.
- Clock and Reset Module This block provides the UDB clocks and reset selection and control.

#### 7.2.1 PLD Module

The primary purpose of the PLD blocks is to implement logic expressions, state machines, sequencers, lookup tables, and decoders. In the simplest use model, consider the PLD blocks as a standalone resource onto which general purpose RTL is synthesized and mapped. The more common and efficient use model is to create digital functions from a combination of PLD and datapath blocks, where the PLD implements only the random logic and state portion of the function while the datapath (ALU) implements the more structured elements.

#### Figure 7-3. PLD 12C4 Structure



One 12C4 PLD block is shown in Figure 7-3. This PLD has 12 inputs, which feed across eight product terms. Each product term (AND function) can be from 1 to 12 inputs wide, and in a given product term, the true (T) or complement (C) of each input can be selected. The product terms are summed (OR function) to create the PLD outputs. A sum can be from 1 to 8 product terms wide. The 'C' in 12C4 indicates that the width of the OR gate (in this case 8) is constant across all outputs (rather than variable as in a 22V10 device). This PLA like structure gives maximum flexibility and insures that all inputs and outputs are permutable for ease of allocation by the software tools. There are two 12C4 PLDs in each UDB.



# 8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses.

- High resolution delta-sigma ADC.
- One 8-bit DAC that provides either voltage or current output.
- Two comparators with optional connection to configurable LUT outputs.
- CapSense subsystem to enable capacitive touch sensing.
- Precision reference for generating an accurate analog voltage for internal analog blocks.



# Figure 8-1. Analog Subsystem Block Diagram

The PSoC Creator software program provides a user friendly interface to configure the analog connections between the GPIO and various analog resources and connections from one analog resource to another. PSoC Creator also provides component libraries that allow you to configure the various analog blocks to perform application specific functions. The tool also generates API interface libraries that allow you to write firmware that allows the communication between the analog peripheral and CPU/Memory.



More information on output formats is provided in the Technical Reference Manual.

#### 8.2.3 Start of Conversion Input

The SoC signal is used to start an ADC conversion. A digital clock or UDB output can be used to drive this input. It can be used when the sampling period must be longer than the ADC conversion time or when the ADC must be synchronized to other hardware. This signal is optional and does not need to be connected if ADC is running in a continuous mode.

#### 8.2.4 End of Conversion Output

The EoC signal goes high at the end of each ADC conversion. This signal may be used to trigger either an interrupt or DMA request.

### 8.3 Comparators

The CY8C32 family of devices contains two comparators in a device. Comparators have these features:

- Input offset factory trimmed to less than 5 mV
- Rail-to-rail common mode input range (VSSA to VDDA)
- Speed and power can be traded off by using one of three modes: fast, slow, or ultra low-power
- Comparator outputs can be routed to lookup tables to perform simple logic functions and then can also be routed to digital blocks
- The positive input of the comparators may be optionally passed through a low pass filter. Two filters are provided
- Comparator inputs can be connections to GPIO or DAC output

#### 8.3.1 Input and Output Interface

The positive and negative inputs to the comparators come from the analog global buses, the analog mux line, the analog local bus and precision reference through multiplexers. The output from each comparator could be routed to any of the two input LUTs. The output of that LUT is routed to the UDB Digital System Interface.







# 8.3.2 LUT

The CY8C32 family of devices contains four LUTs. The LUT is a two input, one output lookup table that is driven by any one or two of the comparators in the chip. The output of any LUT is routed to the digital system interface of the UDB array. From the digital system interface of the UDB array, these signals can be connected to UDBs, DMA controller, I/O, or the interrupt controller.

The LUT control word written to a register sets the logic function on the output. The available LUT functions and the associated control word is shown in Table 8-2.

Table 8-2.	LUT Function	vs. Program	Word and	Inputs
		tor i rogram		mpato

Control Word	Output (A and B are LUT inputs)
0000b	<b>FALSE</b> ('0')
0001b	A AND B
0010b	A AND (NOT B)
0011b	A
0100b	(NOT <b>A</b> ) AND <b>B</b>
0101b	В
0110b	A XOR B
0111b	A OR B
1000b	A NOR B
1001b	A XNOR B
1010b	NOT <b>B</b>
1011b	A OR (NOT B)
1100b	NOT A
1101b	(NOT <b>A</b> ) OR <b>B</b>
1110b	A NAND B
1111b	<b>TRUE</b> ('1')

# 8.4 LCD Direct Drive

The PSoC Liquid Crystal Display (LCD) driver system is a highly configurable peripheral designed to allow PSoC to directly drive a broad range of LCD glass. All voltages are generated on chip, eliminating the need for external components. With a high multiplex ratio of up to 1/16, the CY8C32 family LCD driver system can drive a maximum of 736 segments. The PSoC LCD driver module was also designed with the conservative power budget of portable devices in mind, enabling different LCD drive modes and power down modes to conserve power.

PSoC Creator provides an LCD segment drive component. The component wizard provides easy and flexible configuration of LCD resources. You can specify pins for segments and commons along with other options. The software configures the device to meet the required specifications. This is possible because of the programmability inherent to PSoC devices.

Key features of the PSoC LCD segment system are:

- LCD panel direct driving
- Type A (standard) and Type B (low-power) waveform support
- Wide operating voltage range support (2 V to 5 V) for LCD panels

- Static, 1/2, 1/3, 1/4, 1/5 bias voltage levels
- Internal bias voltage generation through internal resistor ladder
- Up to 62 total common and segment outputs
- Up to 1/16 multiplex for a maximum of 16 backplane/common outputs
- Up to 62 front plane/segment outputs for direct drive
- Drives up to 736 total segments (16 backplane × 46 front plane)
- Up to 64 levels of software controlled contrast
- Ability to move display data from memory buffer to LCD driver through DMA (without CPU intervention)
- Adjustable LCD refresh rate from 10 Hz to 150 Hz
- Ability to invert LCD display for negative image
- Three LCD driver drive modes, allowing power optimization

#### Figure 8-6. LCD System



#### 8.4.1 LCD Segment Pin Driver

Each GPIO pin contains an LCD driver circuit. The LCD driver buffers the appropriate output of the LCD DAC to directly drive the glass of the LCD. A register setting determines whether the pin is a common or segment. The pin's LCD driver then selects one of the six bias voltages to drive the I/O pin, as appropriate for the display data.

#### 8.4.2 Display Data Flow

The LCD segment driver system reads display data and generates the proper output voltages to the LCD glass to produce the desired image. Display data resides in a memory buffer in the system SRAM. Each time you need to change the common and segment driver voltages, the next set of pixel data moves from the memory buffer into the Port Data Registers via DMA.

#### 8.4.3 UDB and LCD Segment Control

A UDB is configured to generate the global LCD control signals and clocking. This set of signals is routed to each LCD pin driver through a set of dedicated LCD global routing channels. In addition to generating the global LCD control signals, the UDB also produces a DMA request to initiate the transfer of the next frame of LCD data.



# 9.2 Serial Wire Debug Interface

The SWD interface is the preferred alternative to the JTAG interface. It requires only two pins instead of the four or five needed by JTAG. SWD provides all of the programming and debugging features of JTAG at the same speed. SWD does not provide access to scan chains or device chaining. The SWD clock frequency can be up to 1/3 of the CPU clock frequency.

SWD uses two pins, either two of the JTAG pins (TMS and TCK) or the USBIO D+ and D– pins. The USBIO pins are useful for in system programming of USB solutions that would otherwise require a separate programming connector. One pin is used for the data clock and the other is used for data input and output.

SWD can be enabled on only one of the pin pairs at a time. This only happens if, within 8  $\mu$ s (key window) after reset, that pin pair

(JTAG or USB) receives a predetermined acquire sequence of 1s and 0s. If the NVL latches are set for SWD (see Section 5.5), this sequence need not be applied to the JTAG pin pair. The acquire sequence must always be applied to the USB pin pair.

SWD is used for debugging or for programming the flash memory.

The SWD interface can be enabled from the JTAG interface or disabled, allowing its pins to be used as GPIO. Unlike JTAG, the SWD interface can always be reacquired on any device during the key window. It can then be used to reenable the JTAG interface, if desired. When using SWD or JTAG pins as standard GPIO, make sure that the GPIO functionality and PCB circuits do not interfere with SWD or JTAG use.



## Figure 9-2. SWD Interface Connections between PSoC 3 and Programmer

<sup>1</sup> The voltage levels of the Host Programmer and the PSoC 3 voltage domains involved in Programming should be the same. XRES pin (XRES\_N or P1[2]) is powered by V<sub>DDI01</sub>. The USB SWD pins are powered by V<sub>DDD</sub>. So for Programming using the USB SWD pins with XRES pin, the V<sub>DDD</sub>, V<sub>DDI01</sub> of PSoC 3 should be at the same voltage level as Host V<sub>DD</sub>. Rest of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programmer. The Port 1 SWD pins are powered by V<sub>DDI01</sub>. So V<sub>DDI01</sub> of PSoC 3 should be at same voltage level as host Programmer. The Port 1 SWD pins are powered by V<sub>DDI01</sub>. So V<sub>DDI01</sub> of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI02</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programming. Rest of PSoC 3 voltage domains (V<sub>DDD</sub>, V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI01</sub>, Rest of PSoC 3 voltage domains (V<sub>DDD</sub>, V<sub>DDA</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programmer.

<sup>2</sup> Vdda must be greater than or equal to all other power supplies (Vddd, Vddio's) in PSoC 3.

- <sup>3</sup> For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio's) to PSoC 3. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.
- <sup>4</sup> P1[2] will be configured as XRES by default only for 48-pin devices (without dedicated XRES pin). For devices with dedicated XRES pin, P1[2] is GPIO pin by default. So use P1[2] as Reset pin only for 48pin devices, but use dedicated XRES pin for rest of devices.



Figure 11-1. Active Mode Current vs  $F_{CPU}$ ,  $V_{DD}$  = 3.3 V, Temperature = 25 °C



Figure 11-3. Active Mode Current vs  $V_{\text{DD}}$  and Temperature,  $F_{\text{CPU}}$  = 24 MHz



Figure 11-2. Active Mode Current vs Temperature and F<sub>CPU</sub>,  $V_{DD} = 3.3 V$ 



#### Notes

25. If V<sub>CCD</sub> and V<sub>CCA</sub> are externally regulated, the voltage difference between V<sub>CCD</sub> and V<sub>CCA</sub> must be less than 50 mV. 26. Sleep timer generates periodic interrupts to wake up the CPU. This specification applies only to those times that the CPU is off. 27. Externally regulated mode.

Based on device characterization (not production tested).
 Based on device characterization (not production tested). USBIO pins tied to ground (V<sub>SSD</sub>).



# Figure 11-15. GPIO Output High Voltage and Current





# Figure 11-16. GPIO Output Low Voltage and Current

# Table 11-10. GPIO AC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
TriseF	Rise time in Fast Strong Mode <sup>[38]</sup>	3.3 V V <sub>DDIO</sub> Cload = 25 pF	-	-	6	ns
TfallF	Fall time in Fast Strong Mode <sup>[38]</sup>	3.3 V V <sub>DDIO</sub> Cload = 25 pF	-	-	6	ns
TriseS	Rise time in Slow Strong Mode <sup>[38]</sup>	3.3 V V <sub>DDIO</sub> Cload = 25 pF	_	-	60	ns
TfallS	Fall time in Slow Strong Mode <sup>[38]</sup>	3.3 V V <sub>DDIO</sub> Cload = 25 pF	-	-	60	ns
	GPIO output operating frequency					
	$2.7 \text{ V} \leq \text{V}_{\text{DDIO}} \leq 5.5 \text{ V}$ , fast strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	-	-	33	MHz
Fgpioout	1.71 V $\leq$ V <sub>DDIO</sub> < 2.7 V, fast strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	-	-	20	MHz
	$3.3 \text{ V} \leq \text{V}_{\text{DDIO}} \leq 5.5 \text{ V}$ , slow strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	_	-	7	MHz
	1.71 V $\leq$ V <sub>DDIO</sub> < 3.3 V, slow strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	-	-	3.5	MHz
Fanioin	GPIO input operating frequency					
' gpiolit	$1.71 \text{ V} \le \text{V}_{\text{DDIO}} \le 5.5 \text{ V}$	90/10% V <sub>DDIO</sub>	-	-	33	MHz

<sup>38.</sup> Based on device characterization (Not production tested).



Table 11-12. SIO AC Specifications (continued)

Parameter	Description	Conditions	Min	Тур	Max	Units
	SIO output operating frequency					
	2.7 V < V <sub>DDIO</sub> < 5.5 V, Unregu- lated output (GPIO) mode, fast strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	-	-	33	MHz
	1.71 V < V <sub>DDIO</sub> < 2.7 V, Unregu- lated output (GPIO) mode, fast strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	_	-	16	MHz
	3.3 V < V <sub>DDIO</sub> < 5.5 V, Unregu- lated output (GPIO) mode, slow strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	-	-	5	MHz
Fsioout	1.71 V < V <sub>DDIO</sub> < 3.3 V, Unregu- lated output (GPIO) mode, slow strong drive mode	90/10% V <sub>DDIO</sub> into 25 pF	_	-	4	MHz
	$2.7 V < V_{DDIO} < 5.5 V$ , Regulated output mode, fast strong drive mode	Output continuously switching into 25 pF	_	-	20	MHz
	1.71 V < V <sub>DDIO</sub> < 2.7 V, Regulated output mode, fast strong drive mode	Output continuously switching into 25 pF	-	-	10	MHz
	1.71 V < V <sub>DDIO</sub> < 5.5 V, Regulated output mode, slow strong drive mode	Output continuously switching into 25 pF	_	-	2.5	MHz
Esioin	SIO input operating frequency					
1 3011	$1.71 \text{ V} \le \text{V}_{\text{DDIO}} \le 5.5 \text{ V}$	90/10% V <sub>DDIO</sub>	_	-	33	MHz

# Figure 11-20. SIO Output Rise and Fall Times, Fast Strong Mode, $V_{DDIO}$ = 3.3 V, 25 pF Load



Figure 11-21. SIO Output Rise and Fall Times, Slow Strong Mode,  $V_{\mbox{DDIO}}$  = 3.3 V, 25 pF Load





# 11.5.5 Current Digital-to-analog Converter (IDAC)

All specifications are based on use of the low-resistance IDAC output pins (see Pin Descriptions on page 12 for details). See the IDAC component data sheet in PSoC Creator for full electrical specifications and APIs.

Unless otherwise specified, all charts and graphs show typical values.

Table 11-26. IDAC DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
	Resolution		-	-	8	bits
I <sub>OUT</sub>	Output current at code = 255	$\begin{array}{l} \mbox{Range = 2.04 mA, code = 255,} \\ \mbox{V}_{\mbox{DDA}} \geq 2.7 \mbox{ V, Rload = 600 } \Omega \end{array}$	-	2.04	-	mA
		Range = 2.04 mA, high speed mode, code = 255, $V_{DDA} \leq 2.7$ V, Rload = 300 $\Omega$	_	2.04	-	mA
		Range = 255 $\mu$ A, code = 255, Rload = 600 $\Omega$	_	255	_	μA
		Range = 31.875 $\mu$ A, code = 255, Rload = 600 $\Omega$	-	31.875	-	μA
	Monotonicity		_	-	Yes	
Ezs	Zero scale error		_	0	±1	LSB
Eg	Gain error	Range = 2.04 mA, 25 °C	-	-	±2.5	%
		Range = 255 µA, 25 ° C	-	-	±2.5	%
		Range = 31.875 µA, 25 ° C	-	-	±3.5	%
TC_Eg	Temperature coefficient of gain error	Range = 2.04 mA	_	-	0.04	% / °C
		Range = 255 µA	-	-	0.04	% / °C
		Range = 31.875 µA	_	-	0.05	% / °C
INL	Integral nonlinearity	Sink mode, range = $255 \mu$ A, Codes 8 – 255, Rload = 2.4 k $\Omega$ , Cload = 15 pF	_	±0.9	±1	LSB
		Source mode, range = 255 $\mu$ A, Codes 8 – 255, Rload = 2.4 k $\Omega$ , Cload = 15 pF	_	±1.2	±1.6	LSB
DNL	Differential nonlinearity	Sink mode, range = 255 $\mu$ A, Rload = 2.4 k $\Omega$ , Cload = 15 pF	_	±0.3	±1	LSB
		Source mode, range = 255 $\mu$ A, Rload = 2.4 kΩ, Cload = 15 pF	-	±0.3	±1	LSB
Vcompliance	Dropout voltage, source or sink mode	Voltage headroom at max current, Rload to $V_{DDA}$ or Rload to $V_{SSA}$ , $V_{DIFF}$ from $V_{DDA}$	1	-	-	V



Figure 11-28. IDAC DNL vs Input Code, Range = 255  $\mu\text{A},$  Source Mode



Figure 11-30. IDAC INL vs Temperature, Range = 255  $\mu A,$  High speed mode



Figure 11-29. IDAC DNL vs Input Code, Range = 255  $\mu\text{A},$  Sink Mode



Figure 11-31. IDAC DNL vs Temperature, Range = 255  $\mu\text{A},$  High speed mode







# 11.5.6 Voltage Digital to Analog Converter (VDAC)

See the VDAC component datasheet in PSoC Creator for full electrical specifications and APIs.

Unless otherwise specified, all charts and graphs show typical values.

# Table 11-28. VDAC DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
	Resolution		-	8	-	bits
INL1	Integral nonlinearity	1 V scale	-	±2.1	±2.5	LSB
INL4	Integral nonlinearity <sup>[52]</sup>	4 V scale	-	±2.1	±2.5	LSB
DNL1	Differential nonlinearity	1 V scale	-	±0.3	±1	LSB
DNL4	Differential nonlinearity <sup>[52]</sup>	4 V scale	-	±0.3	±1	LSB
Rout	Output resistance	1 V scale	-	4	-	kΩ
		4 V scale	-	16	-	kΩ
V <sub>OUT</sub>	Output voltage range, code = 255	1 V scale	-	1.02	-	V
		4 V scale, V <sub>DDA</sub> = 5 V	-	4.08	-	V
	Monotonicity		_	_	Yes	-
V <sub>OS</sub>	Zero scale error		_	0	±0.9	LSB
Eg	Gain error	1 V scale	-	-	±2.5	%
		4 V scale	_	_	±2.5	%
TC_Eg	Temperature coefficient, gain error	1 V scale	_	_	0.03	%FSR / °C
		4 V scale	-	-	0.03	%FSR/°C
I <sub>DD</sub>	Operating current	Low speed mode	-	-	100	μA
		High speed mode	_	_	500	μA

# Figure 11-40. VDAC INL vs Input Code, 1 V Mode



# Figure 11-41. VDAC DNL vs Input Code, 1 V Mode



Note 52. Based on device characterization (Not production tested).



#### 11.8.5 SWD Interface



# Table 11-63. SWD Interface AC Specifications<sup>[67]</sup>

Parameter	Description	Conditions	Min	Тур	Max	Units
f_SWDCK	SWDCLK frequency	$3.3~V \leq V_{DDD} \leq 5~V$	Ι	-	14 <sup>[68]</sup>	MHz
		$1.71 \text{ V} \leq \text{V}_{DDD} < 3.3 \text{ V}$	Ι	-	7 <sup>[68]</sup>	MHz
		1.71 V $\leq$ V <sub>DDD</sub> < 3.3 V, SWD over USBIO pins	_	_	5.5 <sup>[68]</sup>	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	T = 1/f_SWDCK max	T/4	-	-	
T_SWDI_hold	SWDIO input hold after SWDCK high	T = 1/f_SWDCK max	T/4	-	-	
T_SWDO_valid	SWDCK high to SWDIO output	T = 1/f_SWDCK max	-	_	2T/5	

#### 11.8.6 SWV Interface

# Table 11-64. SWV Interface AC Specifications<sup>[30]</sup>

Parameter	Description	Conditions	Min	Тур	Max	Units
	SWV mode SWV bit rate		-	—	33	Mbit

# 11.9 Clocking

Specifications are valid for –40 °C  $\leq$  T<sub>A</sub>  $\leq$  85 °C and T<sub>J</sub>  $\leq$  100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.9.1 Internal Main Oscillator

# Table 11-65. IMO DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
	Supply current					
24 MHz – USB modeV24 MHz – non USB mode		With oscillator locking to USB bus	-	-	500	μA
			-	-	300	μA
	12 MHz		-	_	200	μA
	6 MHz		-	-	180	μA
	3 MHz		—	_	150	μA

Notes

67. Based on device characterization (Not production tested). 68. f\_SWDCK must also be no more than 1/3 CPU clock frequency.



Description Title: PSoC <sup>®</sup> 3: CY8C32 Family Data Sheet Programmable System-on-Chip (PSoC <sup>®</sup> ) (continued) Document Number: 001-56955						
Revision	ECN	Submission Date	Orig. of Change	Description of Change		
*L	3464258	12/14/2011	MKEA	Updated Analog Global specs Updated IDAC range Modified VDDIO description in Section 3 Added note on Sleep and Hibernate modes in the Power Modes section Updated Boost Converter section Updated conditions for Inductive boost AC specs Added VDAC/IDAC noise graphs and specs Added vDAC/IDAC noise graphs and specs Added pin capacitance specs for ECO pins Removed C <sub>L</sub> from 32 kHz External Crystal DC Specs table. Added reference to AN54439 in Section 6.1.2.2 Deleted T_SWDO_hold row from the SWD Interface AC Specifications table Removed Pin 46 connections in "Example Schematic for 100-pin TQFP Part with Power Connections" Updated Active Mode IDD description in Table 11-2. Added I <sub>DDDR</sub> and I <sub>DDAR</sub> specs in Table 11-2. Replaced "total device program time" with T <sub>PROG</sub> in Flash AC specs table Added I <sub>GPIO</sub> , I <sub>SIO</sub> and I <sub>USBIO</sub> specs in Absolute Maximum Ratings Added conditions to I <sub>CC</sub> spec in 32 kHz External Crystal DC Specs table. Updated TCV <sub>OS</sub> value Removed Boost Efficiency vs V <sub>OUT</sub> graph Updated boost graphs Updated min value of GPIO input edge rate Removed 3.4 Mbps in UDBs from I2C section Updated USBIO Block diagram; added USBIO drive mode description Updated JSIO Block diagram Changed max IMO startup time to 12 µs Added note for I <sub>IL</sub> spec in USBIO DC specs table Updated GPIO Block diagram Updated Voltage reference specs Added text explaining power supply ramp up in Section 11-4.		